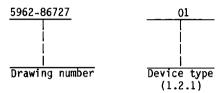
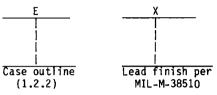
REVISIONS LTR DESCRIPTION DATE **APPROVED** REV PAGE REV **REV STATUS OF PAGES** PAGES 10 2 PREPARED BY ITARY DRAWING **Defense Electronics** mind W. Onoun as **Supply Center** This drawing is available for use by Dayton, Ohio all Departments and Agencies of the Department of Defense MICROCIRCUIT, DIGITAL, BIPOLAR, BCD COUNTER, MONOLITHIC SILICON TITLE: **Original date** of drawing: CODE IDENT. NO. SIZE DWG NO. 5962-86727 23 February 1987 14933 Α AMSC N/A REV PAGE OF 1 11 5962-E184-4



- 1. SCOPE
- 1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of $\overline{\text{MIL}}$ -STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".
 - 1.2 Part number. The complete part number shall be as shown in the following example:





1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type Generic number Circuit function

01 93\$16 Four Bit Binary Counter

1.2.2 <u>Case outlines</u>. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter

Case outline

Ē

D-2 (16 lead 1/4" x 7/8"), dual-in-line package F-5 (16 lead 1/4" x 3/8"), flat package

2

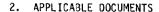
1.3 Absolute maximum ratings.

1.4 Recommended operating conditions.

Supply voltage (V_{CC})- - - - - - - - - - +4.5 V to +5.5 V Minimum high-level input voltage (V_{IH})- - - +2.0 V Maximum low-level input voltage (V_{IL}) - - - - +0.8 V Ambient operating temperature range (T_A)- - - -55°C to +125°C

 $\overline{\text{I/}}$ Must withstand the added PD due to short circuit test (e.g., IOS).

MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO SIZE CODE IDENT. NO. DWG NO. 14933 5962-86727 REV PAGE



2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

- Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - 3. REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
 - 3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.
 - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended ambient operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

	SiZE	CODE IDENT, NO.	DWG NO.
MILITARY DRAWING	4	14933	5962-86727
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV	PAGE 3

	TABLE I.	Electrical perfor	rmance characteris	stics.		
Test	 Symbol 	Condit -55°C < T _A unless otherw	ions < +125°C ise specified	Group A	Limits Min Max 	 Unit
High level output voltage	VOH	$ V_{CC} = 4.5 \text{ V} I_{OH}$ $ V_{IN} = 9.8 \text{ V} \text{or } 2$	= -1.0 mA .O V	1 1, 2, 3	 2.5] V
Low level output voltage	I VOL	$ V_{CC} = 4.5 \text{ V} I_{OL} $ $ V_{IN} = 0.8 \text{ V} Or ^2$	= 20 mA .0 V	1, 2, 3	0.5	
Input clamp voltage	IAIC	1 V _{CC} = 4.5 V I _{IV}	= -18 inA	1, 2, 3	-1.2	 V
Low level input current	III		IP; MR; CEP	1, 2, 3	1-2.0	I mA
	}] [CET	1, 2, 3	-3.0	1 mA
		 	IPE	1, 2, 3	 -4.0 	mA
	 	 	ICP I	1, 2, 3	 -5.0 	 mA
High level input current	I IH		IP; MR; CEP	1, 2, 3	 50 	! µА
		 	CET	1, 2, 3	 75 	 μ Α
	 	! 	I IPE I	1, 2, 3	100	μ Α
			ICP	1, 2, 3	125	μA

 $V_{CC} = 5.5 \text{ V} \quad V_{IN} = 5.5 \text{ V}$

 $V_{CC} = 5.5 \text{ V } V_{OUT} = 0 \text{ V } 1/$

 V_{CC} = 5.5 V | Measured with \overline{MR} = 0 V, all other linputs high and all outputs open

See footnotes at end of table.

Short circuit output current I_{OS}

ICC

MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER	SIZE A	14933	DWG NO. 5962-36727
DAYTON, OHIO		REV	PAGE 4

1 1, 2, 3 |

1, 2, 3

i 1, 2, 3 i-40 i-100 i

mΑ

mΑ

πA

1.0

127

Supply current

TABLE	I. Elect	rical performance	e characteristics	- Continued.			
Test	 Symbol	Condi	tions	 Group A	Limits		 Unit
	<u> </u>	-55°C < T unless other	tions A ≤ +125°C wise specified	subgroups	Min	Max	Γ
Propagation delay from clock to Q output	t _{PLH1}	R _L = 280 Ω C _L = 15 pF	$T_A = 25^{\circ}C$	9 9 	 	9	 ns
	ļ 	 <u> </u>	3/	9,10,11		11	l ns
	 t _{PHL1} 	[] [Ta = 25°C	9	 	13	 ns
		 	3/	9,10,11		15	ns
Propagation delay from clock to T _C	tpLH2	 	 T _A = 25°C <u>2/</u>] 9 		18	ns
	 	 	3/	9,10,11	1	20	ns
	I ^t PHL2] 	T _A = 25°C	9	1	12	ns
	 	 	3/	9,10,11		14	ns
Propagation delay from CET to T _C	 tpLH3] 	TA = 25°C	9 1	 	10 	ns
	 	 	3/	9,10,11	l	12	ns
	t _{PHL3}] 	Ta = 25°C 2/	9	 	10	ns
] []	3/	9,10,11	l l	11	ns
Propagation delay from	t _{PHL4}	 	T _A = 25°C 2/	9	1	20	ns
	!	l 	3/	9,10,11	i I	22	ns

See footnotes at end of table.

MILITARY DRAWING	SIZE A	14933	D w G NO. 5962-86727
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV	PAGE 5

	A	
 C1 4 1		_,

TABLE	I. Electr	ical performance ch	aracteristics - (Continued.				
Test	Test Symbol Conditions -55°C < T _A < +125°C unless otherwise specified				p A Limits proups Min Max		Unit	
Recovery time for MR (inactive)	t _{rec}		$ T_A = 25^{\circ}C$ $\frac{2}{1}$	9	6	 - -	 ns 	
			3/	9,10,11	8		ns	
Master reset (MR) pulse width	t _{pw1}		T _A = 25°C 2/	9	13	 	ns	
			<u>3/</u>	9,10,11	17	 	ns	
Clock pulse width	t _{pw2}	2/	IT _A = 25°C IHIGH	9	6	 	ns	
			LOW	9,10,11	10	 	ns	
		3/	T _A = 25°C HIGH	9	8		ns	
			LOW	9,10,11 9,10,11	13	<u> </u>	ns	
Data setup time	t _{s1}		T _A = 25°C <u>2</u> /		8		ns	
			3/	9,10,11	10		ns	
Data hold time	t _{h1}		T _A = 25°C 2/	9	0		ns	
			3/	9,10,11	0		ns	
PE setup time	t _{s2}		T _A = 25°C 2/	9	16		ns	
			3/	9,10,11	21		ns	
PE hold time	t _{h2}		TA = 25°C 2/	9	0		ns	
			3/	9,10,11	0		ns	

See footnotes at end of table.

MILITARY DRAWING	SIZE A	14933	DWG NO. 5962-86727	•
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV	PAGE 6	

TABLI	E I. Electri	ical performance char	racteristics -	- Continued.			
Test	Symbol	Symbol Conditions Group A				nits	 Unit
		Conditions -55°C < T _A < + unless otherwise	125°C specified	subgroups 	Min	Max	Г <u> </u>
CEP or CET setup time	 t _s 3		$T_A = 25^{\circ}C$	9	12	 	 ns
)` 	3/	9,10,11	16	[[l ns
CEP or CET hold time			T _A = 25°C 2/	9	0	 	l ns
		` 	3/	9,10,11	0		 ns
	i i	i		i i			ĺ

^{1/} Not more than one output should be shorted at a time, and the duration of the short circuit condition should not exceed one second.

 $\frac{2}{V_{CC}} = 5.0 \text{ V}.$

 $\frac{3}{2}$ / $V_{CC} = 4.5 \text{ V}$ to 5.5 V.

- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-983 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 <u>Verification and review</u>. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening.</u> Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test (method 1015 of MIL-STD-883).
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

MILITARY DRAWING	SIZE	14933	DWG NO. 5962-35727	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO		REV	PAGE 7	

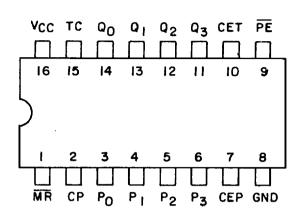


FIGURE 1. Terminal connections.

	Inputs							 	Ou-	tputs		
СР	I MR	I PE	CEP	CET	P ₀	 P ₁	IP ₂	P ₃	Q ₀	Q ₁	Q ₂	Q ₃
Х	L	X 	l X	l X	l X	X	i x	X	L	 L 	L	l L
1	 H 	I L 	l X	X	00	01	lo ₂	D ₃	D _O	 D ₁	ID ₂	 D ₃
1	i H	 H 	l L	L	X	X	i x	X	NC	I NC	I NC	I NC
1	 H 	1 H 	l L	 H 	l X	X	X	X	I NC	NC	NC	NC
1	 H 	 H 	 H 	L	X	I X	i x	X	I NC	NC	NC	NC
1	 H 	 H 	I I н	I I H	i x	X	X	Х		Сог	ınt	

H = High level L = Low level X = Don't care

NC = No change

D_j may be either hi**g**h or low ↑ Low-to-high Transition

FIGURE 2. Truth table.

MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER	SIZE A	CODE IDENT. NO. 14933	DWG NO.	5962-86	727
DAYTON, OHIO		REV		PAGE	8

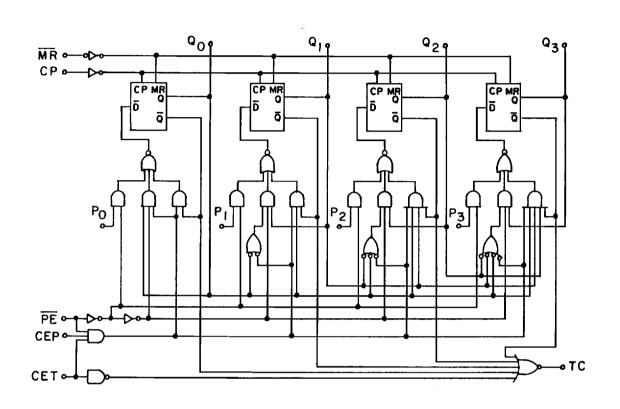
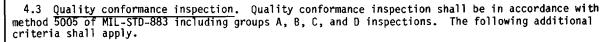


FIGURE 3. Logic diagram.

MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO	SIZE A	14933	DWG NO. 5962-86727	
		REV	PAGE 9	



4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroups 7 and 8 tests shall verify the truth table.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
 - (1) Test condition C or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	
Final electrical test parameters (method 5004) 	1*,2,3,7,8,9, 10,11
Group A test requirements (method 5005)	1,2,3,7,8,9, 10**,11**
Groups C and D end-point electrical parameters (method 5005)	1,2,3

^{*} PDA applies to subgroup 1.

MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO	SIZE	14933	DWG NO. 5962-86727
	REV		PAGE 10

^{**}Subgroups 10 and 11, if not tested, shall be guaranteed to the limits specified in table I.

- PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
- 5. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.
- 5.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1</u> /		
5962-8672701EX	34335	93S16/BEA		
5962-86727@1FX	34335	93S16/BFA		

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

34335

Vendor name and address

Advanced Micro Devices, Inc. 901 Thompson Place P.O. Box 3453 Sunnyvale, CA 94088

MILITARY DRAWING

DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO

SIZE	CODE IDENT, NO.		DWG NO.				
А	1.	4933	5962-86727				
		REV		PAGE	11		